

# Krátky popis procesů testování používaných tranzistorovým testerem AVR

## Verze 1.11.k

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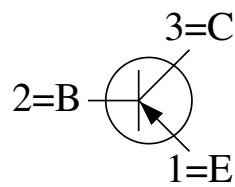
# □ Obsah

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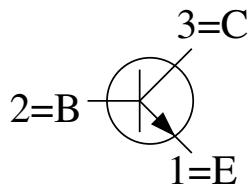
# □ Hlava 1

## □ testování bipolárních tranzistorů

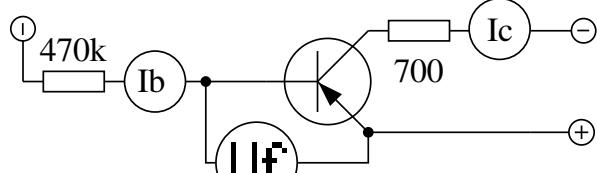
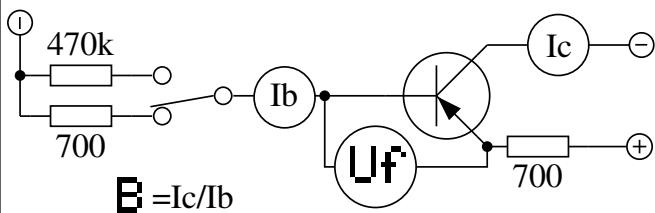
BC640



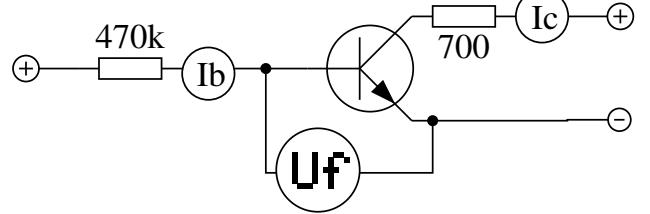
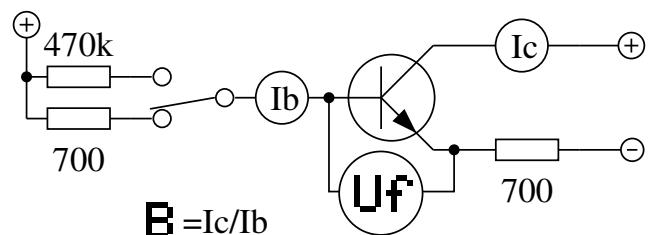
BC639



PNP 123=EBC  
B=185 U<sub>f</sub>=607mV



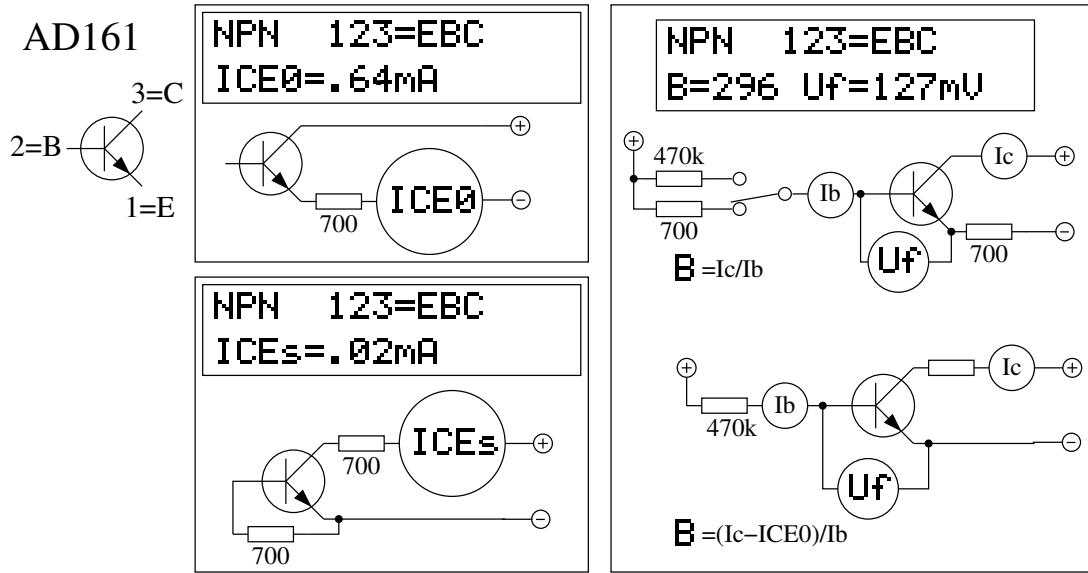
NPN 123=EBC  
B=216 U<sub>f</sub>=632mV



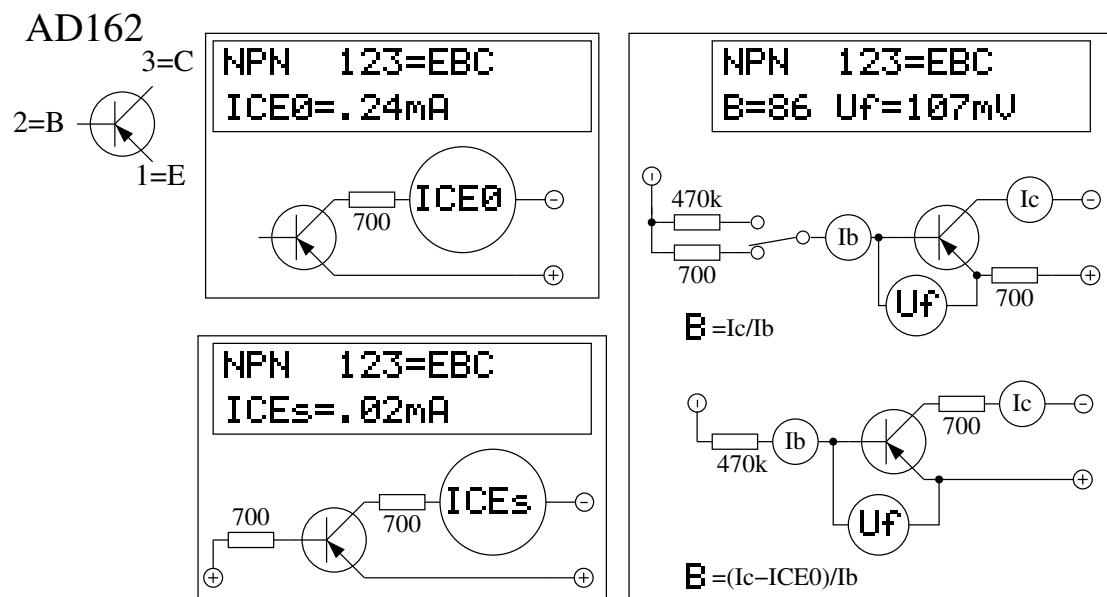
(a) PNP

(b) NPN

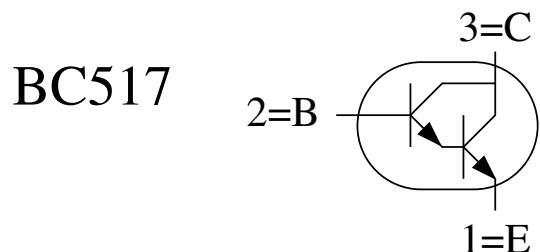
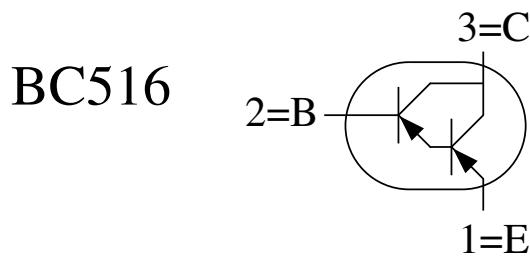
□ br. 1.1 Křemíkové bipolární tranzistory



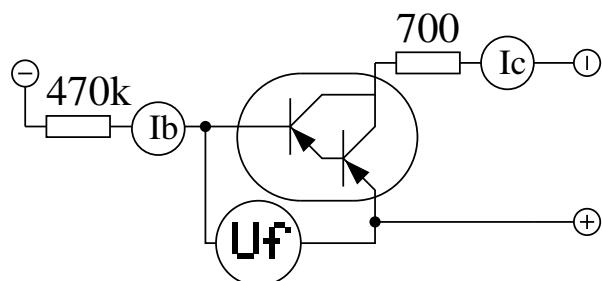
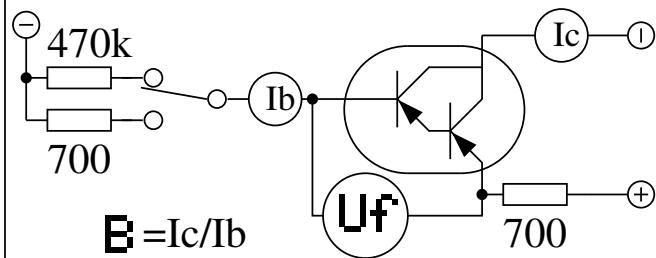
□ Obr. 1.2 □ Germaniové □ NPN □ ramzistory



□ Obr. 1.3 □ Germaniové □ PNP tranzistory

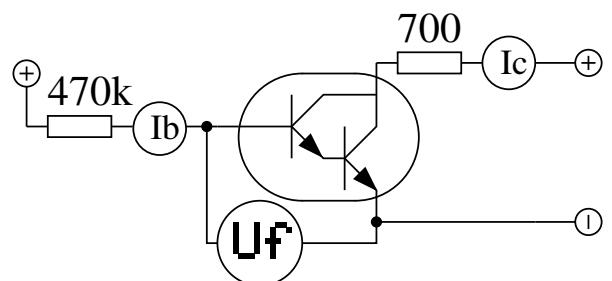
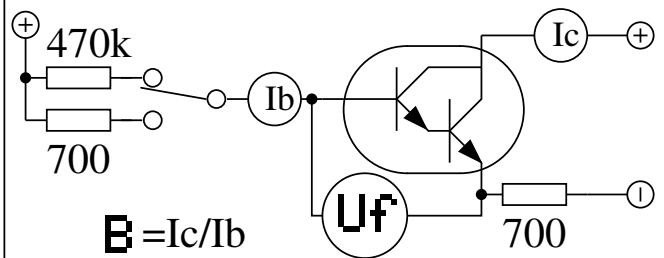


**PNP 123=EBC**  
**B=82.0k Uf=1.20V**



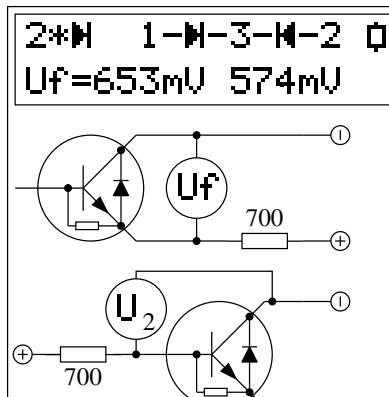
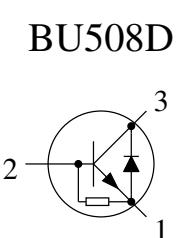
(a) PNP

**NPN 123=EBC**  
**B=26.0k Uf=1.23V**



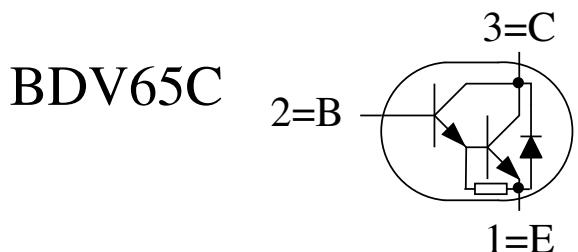
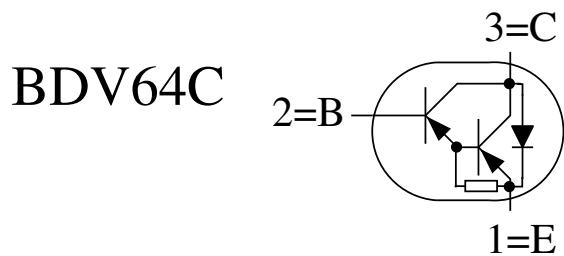
(b) NPN

obr. 1.□ Křemíkové□ tranzistory □Darlington

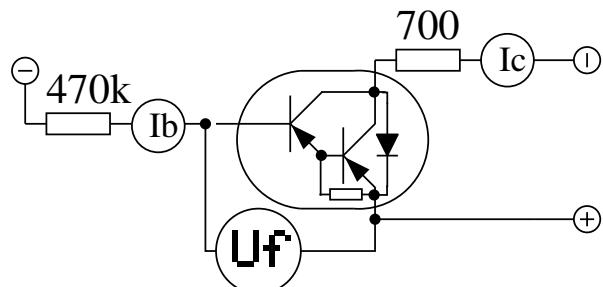
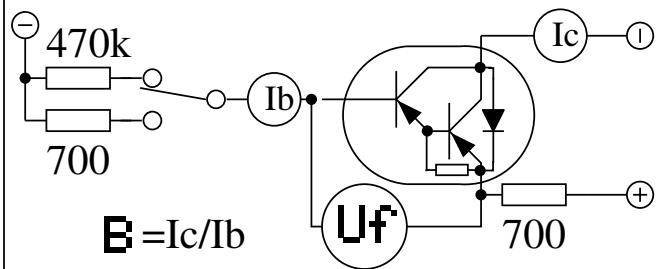


**2\*H 1-c3-2**  
**41.5Ω**

Obr. 1.5. NPN Tranzistory s diodou a odporem

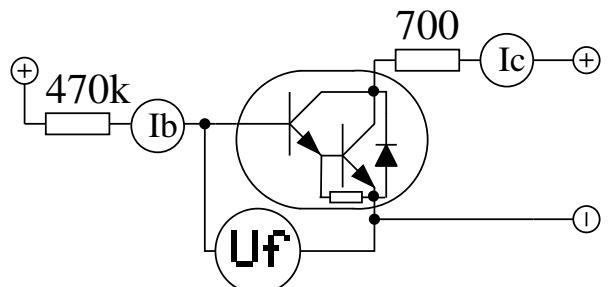
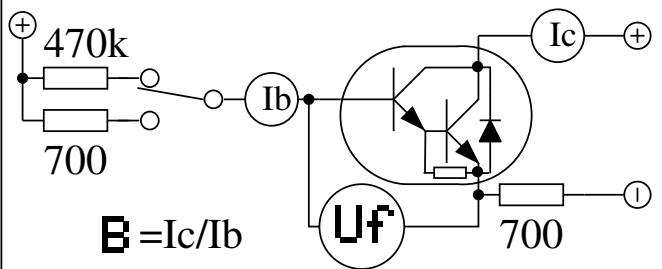


**PNP -■- 123=EBC**  
**B=35 Uf=1.11V**



(a) PNP

**NPN -■- 123=EBC**  
**B=12 Uf=1.11V**

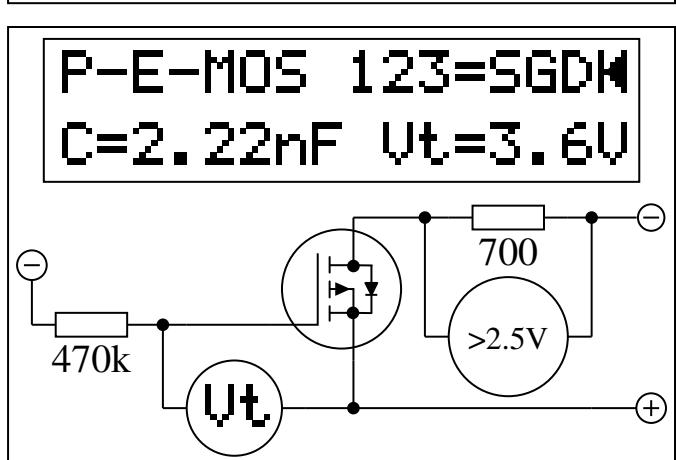
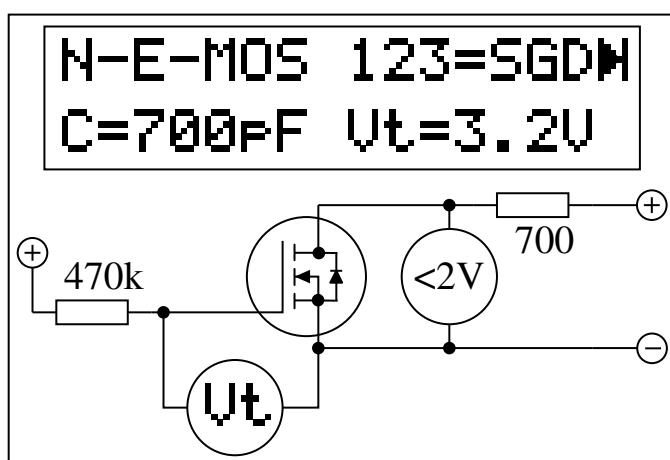
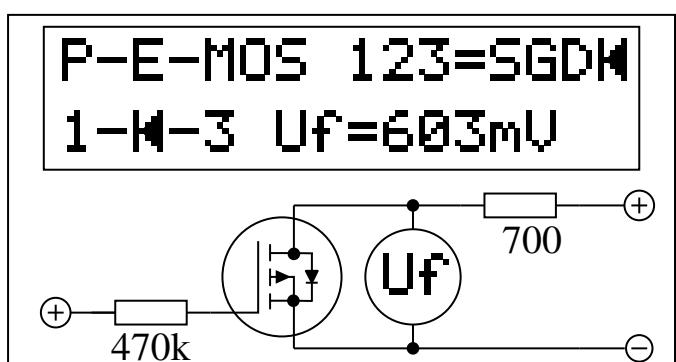
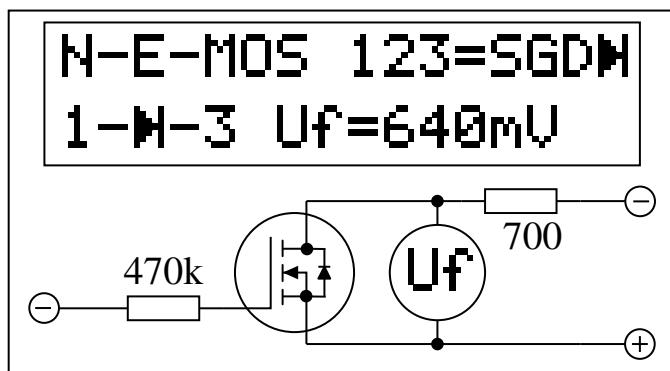
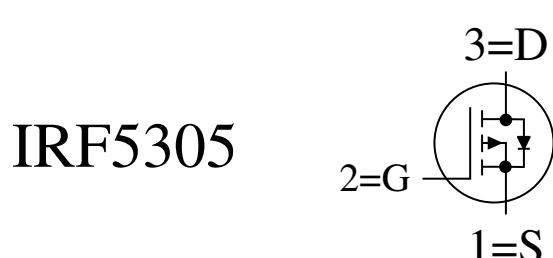
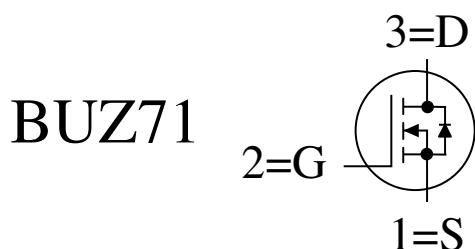


(b) NPN

obr. 1.6 Křemíkové tranzistory Darlington

# Hlava 2

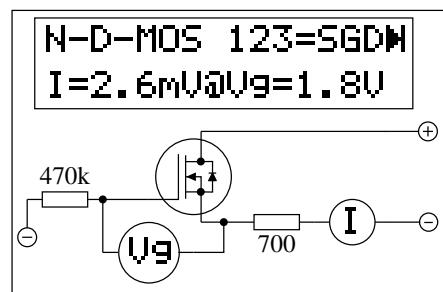
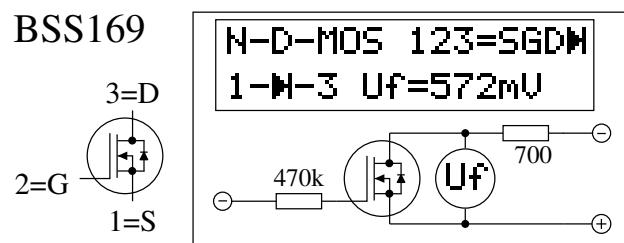
## Testování tranzistorů řízených polem



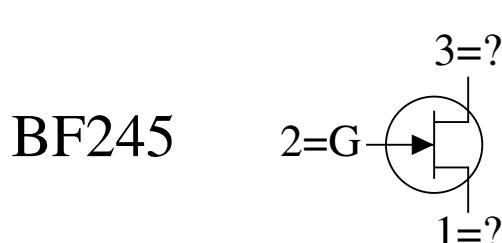
(a) N-E-MOSFET

(b) P-E-MOSFET

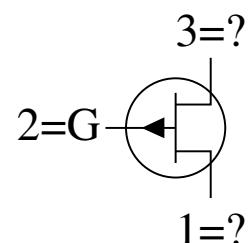
Obr. 2.1. Výkonové MOSFET Tranzistory



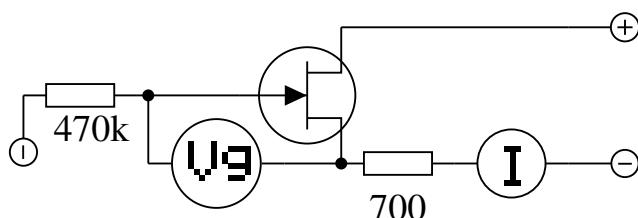
Obr. 2.2. N-D-MOSFET



J175

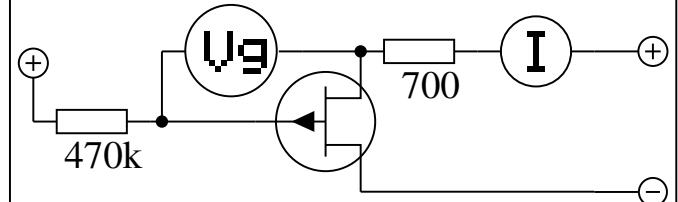


N-JFET 123=DGS  
I=2.5mA@Vg=1.7V



(a) N-JFET

P-JFET 123=SGD  
I=3.2mA@Vg=2.2V



(b) P-JFET

Obr. 2.3. JFET tranzistory

# □Literatura

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